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Structure and Magnetic Properties of $Nd_{0.88}MnO_3$ Films Grown on SrTiO₃ (100) Substrates by liquid-injection MOCVD

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Abstract:

We have investigated the structure and magnetic properties of the Nd_{0.88}MnO₃ (NMO) perovskite thin-film layers by liquid-injection MOCVD tried on SrTiO₃ (STO) (100) substrates. The structural examinations showed that the growing film was amorphous. It changed to the crystalline phase after being annealed at 900 °C in the air for 24 h. A minor secondary phase identified as Mn₃O₄ appears. The film is subjected to in-plane (IP) tensile stress leading to a contraction of the film out of the plane (OOP) lattice parameters. The orientation relationships for the film structure is described near the interface as $[10\bar{1}]NMO/[100]STO$ and [010]NMO/[001]STO. The NMO thin film showed ferromagnetic ordering with a transition temperature T_C =85K. The large bifurcation between ZFC and FC curves with a cusp at T_f = 53 K; and an irreversible temperature T_{irr}= 48 K proves the spin-glass behavior with long-range ferromagnetic order (Mn³⁺-O²⁻-Mn⁴⁺) co-exists in NMO thin films. The magnetic easy axis corresponded to the surface normal.

Keywords: Manganite, Grown thin film, liquid-injection MOCVD, X-ray diffraction, out-ofplane texture, Magnetization, Spin-Glass.

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1. Introduction

Orthorhombic $RMnO_3$ (o- $RMnO_3$, R = La-Lu, Y) which exhibit a perovskite-like structure, have been potential research subjects due to their remarkable states resulting from the fine relationship between charge, spin, orbital, and lattice parameters [1-8]. Moreover, these materials can be epitaxially grown as thin films on different substrates. They exhibit compressive or tensile strains that are attributable to the lattice mismatch among the substrate and the corresponding layer. Hence, the strain produced by epitaxial growth is an efficient manner to obtain films with different transition temperatures, which may replay to different requirements for various scientific applications [9,10]. The bond length mismatch is adjusted in the orthorhombic o-RMnO₃ structure by rotation of the MnO₆ octahedra resulting in bending of the equatorial and azimuthal Mn–O–Mn bond angles θ away from 180° within all three crystallographic axes. These characteristics lead to the A-type antiferromagnetism (AFM) observed below the Neel temperature T_N with ferromagnetic (FM) superexchange interactions in the planar section and AFM interactions within the c-axis perpendicular to a planar section for large ions R= La, Pr, Nd, and Sm [11]. By decreasing the size of the R ion (R= Eu, Gd, Tb, Dy, and Ho); i.e., with increased bending of the Mn–O–Mn bonds, many complex AFM structures have been surveyed. The complex structures with mixed FM/AFM superexchange interactions in the ab-plane have been accounted for as the next-nearestneighbor anisotropic relations. These relations occur from the closer distance and the less screened exchanges between the Mn ions [12]. The rare-earth manganite NdMnO₃ belongs to the group of orthorhombically-distorted perovskites RMnO₃ with the GdFeO₃ symmetry. Among some perovskite-like oxides, the Nd-based samples exhibit a larger lattice distortion due to the little size of Nd atoms [13]. In thin-film form, the in-depth structural characterization and study of the magnetic behavior of Lacunar neodymium manganite were not addressed previously. Structural and magnetic results were only briefly published in the EPJ Web of Conferences [14] as a support of the interpretation of our structural and magnetic measurements. This article aims to provide complete information regarding this specimen.

2. Experimental procedure

NMO films were synthesized by injection MOCVD "band flash". An in-depth report of this experimental procedure has been detailed in Ref. [15]. The resulting study of the Nd/Mn relative amount in the initial solution on the film composition was released by grown of lacunar perovskite-type manganese oxides Nd_{1-x}MnO₃ films of about 200 nm thickness on

STO with a different Nd/Mn composition. The substrate temperature was at 680 °C. The injections number is estimated at 1000 with a frequency of 1/s, which is equivalent to a growth rate of 0.72 µm/h. The as-deposited samples were then heat-treated, in an in situ manner, at 680 °C for 30 min under an O₂ flow. The Nd/Mn composition of the Nd_{1-x}MnO₃ films, measured by Wavelength Dispersive Spectroscopy (WDS) technique, versus the Nd/Mn composition in the starting solution was performed. However, the oxygen elements in the layer/substrate system make quantitative resolve by WDS of the chemical composition very difficult. A linear relationship among the Nd/Mn composition of precursor blend and that determined on the film has occurred. This investigation indicates the possibility to adjust the film composition. A scheme of the MOCVD reactor utilized in this project is detailed in figure 1(a). Sequence controlling of microliters droplets injected in the reactor (in a cold zone) on a moving tape is giving in figure 1(b). The composition of the solution required to attain a lacunar perovskite-type manganese oxides $Nd_{0.88}MnO_3$ (NMO) is 0.78 which means that the deposition proportion of the Nd(thd)₃ precursor is in small quantities compared to $Mn(thd)_3$ within the deposition states used. The film has a thickness of about 200 nm. X-ray diffraction (XRD) measurements were achieved with a BRUKER D8 advance research diffractometer $\theta/2\theta$ with a Cu anode (λ =1.5406 nm). Magnetization measurements were achieved using squid magnetometers (Quantum Design) in magnetic fields applied along or normal to the film surface. For every M-T curves, the film was cooled down to 10 K in zero magnetic fields, the magnetization measurements were achieved by reheating the film in an applied field of 0.05 T (zero-field cooling magnetization process noted M_{ZFC}). Afterward, the magnetization was obtained even as the sample was being cooled in the same magnetic field (field cooled magnetization process noted M_{FC}). Isothermal magnetizations M versus H curves were measured at 4 K. Crystallographic images have been made with the program CrystalMaker [16].

3. Results and discussion

XRD pattern of the as-grown NMO film is shown in figure 2. It reveals that the film, in its first stage, is completely amorphous without any signal from microcrystals since apart from the STO (100) substrate reflections are apparent. Besides, just a large band in the spectrum is established. No significant turn in the observed XRD data occurred after the first stage of deposition at 680°C. This examination indicates that the NMO layer has remained in an amorphous state after processing. After 24 h anneal at 900°C, a new diffraction peak

appeared. It is clear that the NMO film grows on the STO surface and exhibits a good crystalline state. Highly (100) textured and excellent OOP orientation of the NMO films is obtained. The stabilized phase results in the presence of minor secondary phases identified as Mn₃O₄ according to JCPDS cards 086-2337. To better understand and analyze this structural behavior, we return to an overview of both STO substrate and NMO bulk. STO crystallizes at room temperature in a cubic $Pm\bar{3}m$ structure with $a_{STO} = 3.905$ Å. Bulk ceramic sample NMO forms a distorted orthorhombic symmetry (Pnma space group) at room temperature; the orthorhombic lattice parameters are a = 5.614 Å, b = 7.607 Å, and c = 5.407 Å [17]. This preference of space group fits well with a convention for perovskite thin films. In these systems, the extended axis is marked the b-axis and is frequently chosen to be along to the substrate normal. Here we modify the basis of Ref. [18] so that the b-axis of Pnma maps to the c-axis (rather than b) of the cubic prototype specimen $Pm\overline{3}m$. To compare with the pseudocubic perovskite structure of substrates, we introduce the small orthorhombic lattice defined as $a_p = \frac{a}{\sqrt{2}}$, $b_p = \frac{c}{\sqrt{2}}$, $c_p = \frac{b}{2}$ [19]. We also define a pseudo-cubic symmetry with a mean lattice parameter $a_{pc} = \sqrt[3]{a_p \times b_p \times c_p} = 3.864 \text{ Å}$ which is an almost ideal cubic perovskite. In general, an orthorhombic structure may be viewed conveniently as a cubic one: orthorhombic $[10\overline{1}]o$, [101]o, and [010]o directions correspond to the pseudo-cubic [100]p, [010]p and [001]p directions, respectively. With these defined parameters, the NMO has to face the misfit strain defined as $\varepsilon_{\rm m} = \frac{a_{\rm substrate} - a_{\rm bulk}}{a_{\rm bulk}} = 1.10\%$, where $a_{\rm substrate}(a_{\rm STO})$ and a bulk (apc in the pseudo-cubic notation) are respectively the strain-free lattice parameters of the substrate and the film. A diffraction process is observed along with the same sort of the plan (h00) of the pseudocubic perovskite cell as the substrate. The phase, therefore, appears to be textured in the direction perpendicular to the substrate plane. Moreover, the NMO diffraction peaks roughness and their emplacement close to the (h00) Bragg peaks of STO, indicates a good crystallinity and an OOP [100] texture. To describe more precisely the growth stabilization and the NMO structure, we study the (200) diffraction line of NMO (in the pseudo-cubic notation) which is well dissociated from the corresponding one of the substrate; scans are shown on figure 3. We can see strong film peaks and two very strong substrate overlapping peaks at right and left 2θ angle regions respectively. The clear dissimilarity of the film peaks corresponds to Cu $k_{\alpha 1}$ and $k_{\alpha 2}$ radiation. From the peak positions, it is easy to find that the NMO film is grown with the IP tensile strain which in turn must produce a contraction of the layer OOP lattice distances. The (200) peak of the NMO

film OOP parameter is around 20=47.1°±0.1° and corresponding to a $_{\perp}$ = 3.8600 Å ± 0.005 Å. This value is a little higher than that observed for polycrystalline bulk samples at room temperature a_{pc}, so denoting a small contraction of OOP lattice distances and tensile stress over the IP lattice distance of the NMO. The real corresponding lattice mismatch is $\varepsilon_m = 1.16$ %. The crystal structure of both NMO and STO, as well as a schematic depiction of the growth of NMO $(10\overline{1})$ layer on STO (100) substrate, is demonstrated in figure 4(a) and 4(b) respectively. As shown in the figure, NMO IP (10 $\overline{1}$) and (010) directions are aligned along with (100) and (001) directions of the cubic STO substrate. These structure models of NMO film and STO substrate are constructed by crystallographic simulation software CrystalMaker. Besides, the micro-structural distribution is equivalent to the results of the precedent TEM characterizations, occurred on the strain of other deposed films on STO systems [20-23]. Figure 5 shows the thermal evolution of field cooled $M_{FC}(T)$ and zero field cooled M_{ZFC}(T) magnetization curves measured in 0.05 T of the OOP applied field. The exerted magnetic field H is expressed in SI units as μ_0 H all over this work. The data give evidence to ferromagnetic arrangement under the transition temperature $T_C = 85$ K defined as the inflection point of the derivative dM(T)/dT as shown in the inset (a) of figure 5, where the FC and ZFC measurements separate at $T_{irr} \approx 48$ K (inset (b) of figure 5). The (T_C) magnetic transition temperature of the film is similar to the corresponding values of bulk compounds with little different nominal composition. In NdMnO₃, magnetic ordering takes place at T = 86 K [24] and T=88 K [25], whereas in Nd_{0.9}MnO_{2.85} it occurs at T = 85 K [26]. However, compared to bulk samples, the anisotropy of the magnetization in the thin film is less marked. Figure 6 shows the thermal evolution of field cooled $M_{FC}(T)$ curves measured in the OOP and IP directions in the 0.05 T applied field. Here, we remarked that magnetization M(T) in the OOP direction is twice as large as that in the IP direction. We think that the magnetic properties are related to both systems for controlling lattice mismatch and oxygen octahedral rotation mismatch. Several previous studies such as Monte-Carlo simulations and first-principles calculations founded on the double exchange form provided evidence that the oxygen octahedral rotation plays a more significant part than the superlattice dimension effect and might lead to canted magnetism [27,28]. Moreover, it is well known that the temperature transition T_C depends on the electronic bandwidth (W) [29,30] which is characterized by the overlap between the orbital d of Mn and the orbital p of O^{2-} and which can be empirically described by the equation [31]:

$$W(a.u.) = \frac{\cos[\frac{1}{2}(\pi - \theta_{Mn-O-Mn})]}{(d_{Mn-O})^{3.5}}$$

Where $\theta_{Mn-O-Mn}$ and d_{Mn-O} are the Mn-O-Mn bond angle and the Mn-O bond length respectively. The bond angle $\theta_{Mn-O-Mn}$ diminishes with the disappearance of the octahedral rotations contradicting the fact that ferromagnetism should be improved. A variation of the eg occupants owing to biaxial strain can reduce temperature transition T_C depending on the distribution homogeneity of the given tetragonality near the interface between film and substrate. Because of the complexity of the factors involved in the evaluation of magnetic behavior such as crystal structure, stoichiometry, strain, temperature, growth conditions, etc., it is difficult to evaluate the precise origin of the magnetism behavior in our NMO/STO system. Figure 7 shows the magnetic hysteresis loop of the NMO thin film at 4 K in an IP and OOP field range 0 to 5 T. by varying the applied magnetic field, a significant difference in the magnetization is observed. The OOP magnetization increased quickly than that measured in the IP direction. Moreover, it seems that the magnetization is not being saturated witch indicates the existence of the antiferromagnetic state. The remanent magnetizations (M_R) and coercive fields (H_C) were determined from the extended local M-H hysteresis loops measured at 4 K (shown in inset Figure 7). These values are (M_R =4.03×10⁻⁴ emu, H_C =0.031 T) and $(M_R=1.60\times10^{-4} \text{ emu}, H_C=0.025 \text{ T})$ for OOP and IP direction respectively. The curve M-H at T = 300 K shows similar paramagnetic behavior for both OOP and IP directions. These behaviors indicate the coexistence of an AFM and FM state in the film [32]. Taking into account all these observations, we can note that ZFC and FC magnetization curves of the NMO thin-film behaves differently. The ZFC magnetization increases progressively to a maximum value around a freezing temperature $T_f = 53$ K by increasing temperature (T_f is defined as (M_{FC}-M_{ZFC})/M_{ZFC}, which becomes different from zero, indicating the onset of a freezing process) and then decreases monotonously. On the contrary, the FC magnetization decreases progressively with increasing temperature. A clear bifurcation of the FC and ZFC with a lambda shaped-like has been observed. These phenomena are collectively treated before as spin-glass system (SG) behaviors, where Tirr is generally close to but slightly below T_f [33-35]. Also, although in the cluster glass (CG) systems, T_{irr} is usually higher than T_f, [36,37]. Here, we can still exclude the superparamagnetic (SPM) system where the magnetization after FC increases rapidly and monotonously with the lowering of the temperature [38]. Creating deficits at the A-site sub-lattices induces a dilution of the magnetic exchange between Mn³⁺ and Mn⁴⁺ ions via oxygen, a disorder, and a change in the Mn³⁺-O²⁻-

 Mn^{4+} bond angle in the system. The balance of competing for superexchange pathways between the transition metals matrix Mn^{3+}/Mn^{4+} state is modified which supports the most likely scenario suggesting a spin-glass behavior with long-range ferromagnetic order (Mn^{3+} - $O^{2-}-Mn^{4+}$) co-exists in NMO thin films [39,40].

4. Conclusion

In summary, we grew high-quality growth NMO ($10\overline{1}$) thin film on STO (100) substrate using liquid-injection MOCVD. Structural analysis shows that the grown film was amorphous, but after annealing at 900°C in the air for 24 h, it changed to the crystalline phase. The NMO thin film showed ferromagnetic ordering with a transition temperature T_C =85K. ZFC and FC magnetization curves split with a sharp cusp in the ZFC curves at a low temperature around the freezing temperature T_f = 53 K and an irreversible temperature T_{irr}= 48 K, indicating spin-glass behavior with long-range ferromagnetic order (Mn³⁺-O²⁻-Mn⁴⁺) and an OOP magnetic easy axis.

5. References

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Figure captions

Figure 1. (a) Scheme of the liquid source injection MOCVD reactor used in this study, (b) injector and a Sequence controlling of microliters droplets injected in the reactor (in a cold zone).

Figure 2. X-ray diffraction patterns of as-deposited NMO thin films for $20^{\circ} < 2\theta < 80^{\circ}$.

Figure 3. X-ray diffraction patterns of as-deposited NMO thin films for $44^{\circ} < 2\theta < 50^{\circ}$.

Figure 4. Schematic diagram showing: (a) Crystal structure of NMO, Crystal structure of STO and Schematic representation of the $(10\overline{1})$ epitaxial growth of orthorhombic LMO thin films on cubic perovskite (100) substrates of STO. (b) The layer's $(10\overline{1})$ and (010) directions are aligned along (100) and (001)directions of the substrate.

Figure 5. Temperature dependence of the field cooled $M_{FC}(T)$ and zero field cooled $M_{ZFC}(T)$ magnetization curves measured in 0.05 T of the out-of-plane applied field. Inset (a) shows the dM/dT curve for determining T_C . Inset (b) shows the method described in the text to calculate the onset of weak and strong irreversibility temperatures from the irreversible magnetization (i.e., $(M_{FC}-M_{ZFC})/M_{ZFC}$).

Figure 6. Thermal evolution of field cooled $M_{FC}(T)$ curves measured in the out-of-plane (OOP) and in-plane (IP) 0.05 T applied field.

Figure 7. M(H) hysteresis loops of NMO film at 4 K and 300K along OOP and IP directions. The inset shows in detail the low field region.













